



1270/1271 X-Y BOARD HITESTER

Automatic Testing Equipment

HIOKI 1270

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Superior cost effectiveness Dual-Sided Bare Board Tester





The 1270/1271 X-Y BOARD HITESTERS are fixtureless, dual-sided, bare board testers that provide superior cost performance. Using a total of four arms, two in front and two in back, it is capable of simultaneously testing both sides of a board, and is available with a 4-terminal resistance measurement function (optional) that allows measurement of very small resistances in IVH or through holes.

> 1270 (Board size : 50 × 50 to 400 × 330mm) 1271 (Board size : 50 × 70 to 610 × 510mm)

HIOKI company overview, new products, environmental considerations and other information are available on our website.

A Wide Range of Test Capabilities

- Detection of short and open circuits with the capacitance measurement method.
- Detection of short open circuits with the continuity detection method.
- Detection of short and open circuits with combined capacitance-resistance measurement method. (Patent No.JP1736393)
- Resistance measurement with IVH (Interstitial Via Hole) or through holes.
- Trace resistance measurement
- Detection of isolated IC pads on IC's.
- Measurement of insulation between networks.

- Detection of high resistance short circuits by capacitance measurement.
- L, C, R, and Diode measurements.

| Number of Arms | 4 (two each, front and back) | | Board Fixation | Height: 1100 ± 15 mm(when placed on an even floor) |
|--------------------------------|---|---------------------------------|---|---|
| Number of Test Steps | 40,000 steps (300,000 for continuous testing) | | | Position: Vertical |
| Test Ranges | DC Measurement Function | | Fixation Method | Cranp method on four edges of board (sides are chucked |
| | Resistance: | 400 $\mu\Omega$ to 40 MQ * | Fixation Method | for the center of the board only) |
| | Capacitance: | $4 \ \mu F$ to $400 \ mF$ | Fixable Boards | Thickness: 0.6 to 3.2 mm |
| | Diodes and Transistors (VF): | 0 to 25 V | | Outer Dimensions: |
| | Zener Diodes (VZ): | 0 to 25 V | | 1270: 50 (W) \times 50 (H) to 400 (W) \times 330 (H) mm |
| | Photocouplers: | 0 to 25 V | | 1271: 50 (W) \times 70 (H) to 610 (W) \times 510 (H) mm |
| | Short Circuit: | $400~m\Omega$ to $40~k\Omega$ | Alignment | Automatic |
| | Open Circuit: | 4Ω to $4 M\Omega$ | Safety Devices | Emergency stop switch, safety cover (anti-static resin), |
| | Voltage: | 0 to 25 V | Safety Devices | arm anti-collision function |
| | AC Measurement Function | Daman Canada | | AC 200 V (single phase), 50/60 Hz |
| | Resistance: | 1m Ω to 100 M Ω * | Power Supply | Power Consumption: 3 kVA |
| | Capacitance: | 10 fF to 10 µF | Operating Environment | Temperature: 23 ± 10 °C |
| | Inductance: | 10 µH to 100 H | | Humidity: 75 % rh maximum (no condensation) |
| Measurement Signal | DC Constant Voltage: 100 m | nV / 400 mV (2 ranges) | | Environment: Avoid use in environments subject to |
| | DC Constant Current: 200 n. | A to 200 mA (13 ranges) | Environment | dust, vibration, or corrosive gases |
| | AC Constant Voltage: 1 V / | 10 V rms (2 ranges) | | Floor Strength: 500 kg/m ² minimum |
| | 160 H: | z / 1.6 kHz / 16 kHz / 160 kHz | Unit Dimensions | 1270:Approx. 1500 (W) × 1800 (H) × 860 (D) mm |
| Measurement Section | DC Voltage Measurement: | | Mass | Approx. 1000 kg |
| | 800 µV to 25 V f.s. (8 ranges) | | *Using the 4-terminal resistance measuring method (optional | |
| | DC Current Measurement: | | | |
| | 100 nA to 25 mA f.s. (7 ranges) | | | |
| | AC Current Measurement: | | Outer Dimensions | |
| | 10 µA to 1 mA rms (3 ranges, for 1 V rms) | | | |
| | 1 µA to 100 µA peak f.s. (3 ranges, for 10 V peak) | | 1270 | E E |
| Decision Range Setting | - 99.9% to + 999.9%, or absolu | ite value | | |
| Measurement Time | 0.015 seconds / step at top speed | | | |
| | (0.15 mm movement with 4-arm simultaneous probing | | • • • | |
| | with capacitance measurement method.) | | | |
| Probing Accuracy | Each arm within \pm 50 μm (X and Y axes, 20 \pm 3 $^{\circ}C)$ | | | |
| Probing Repeatability | Within \pm 20 μm (probing position, same temperature) | | · · · · | |
| Minimum Movement Resolution | X and Y: 1 µm / pulse, Z: 6 µm / pulse | | | |
| Minimum Probing | 0.1 mm between the left and right arms when using | | | |
| Pitch | link probes | | | NU NU KOMBOLEL – 2349 TA KOMBOLE |
| Probe Work Area | 1270 : 394 (W) × 324 (H) mm | 1 | 禹刻 | |
| riobe work Area | $1271 : 604 (W) \times 504 (H) mm$ | 1 | | |

1270/1271 Specifications



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